

FORM PTO-1449
U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

DOCKET NO: 007352 USA/ETCH/DRIE/JB

APPLICATION NO.:
10/615,159

INFORMATION DISCLOSURE STATEMENT
IN AN APPLICATION

APPLICANT: Frum et al.

FILING DATE: 7/7/2003

GROUP ART UNIT:
1763

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
GAG	5	4	5	0	2	0	5	09/12/1995	Sawin, et al.			
	5	5	0	3	7	0	7	04/02/1996	Maung, et al.			
	5	5	6	4	8	3	0	10/15/1996	Bobel, et al.			
	5	6	5	8	4	1	8	08/19/1997	Coronel, et al.			
	5	7	5	6	4	0	0	05/26/1998	Ye, et al.			
	6	0	8	1	3	3	4	06/27/2000	Grimbergen, et al.			
	6	1	6	5	3	1	1	12/26/2000	Collins, et al.			
GAG	4	1	4	7	4	3	5	04/30/1979	Habegger			
	4	8	4	6	9	2	8	07/11/1989	Dolins, et al.			
	4	8	4	7	7	9	2	07/11/1989	Barna, et al.			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
												YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

GAG	Maynard, et al., "Multiwavelength Ellipsometry for Real-time Process Control of the Plasma Etching of Patterned Samples." <u>J. Vac Sci Technol. B</u> , 15 (1), Jan/Feb 1997, pages 109-115 ✓
GAG	Klemens, F.P., et al., "High Density Plasma Gate Etching of 0.12 μ m Devices with Sub 1.5 nm Gate-Oxides." <u>Electrochemical Society Proceedings</u> , Volume 97-30, pages 85-95

EXAMINER

George Goudreau

DATE CONSIDERED

5-041

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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gag	4	8	6	1	4	1	9	08/29/1989	Flinchbaugh, et al.									
FOREIGN PATENT DOCUMENTS																		
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[illegible]

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gag	3	6	1	2	6	9	2	10/12/1971	Kruppa, et al.			
	3	8	2	4	0	1	7	04/01/1975	Galyon			
	3	8	7	4	7	9	7	04/01/1975	Kasai			
	3	9	8	5	4	4	7	10/12/1976	Kruppa, et al.			
	4	1	4	1	7	8	0	02/27/1979	Kleinknecht, et al.			
	4	1	9	8	2	6	1	04/15/1980	Busta, et al.			
	4	2	0	8	2	4	0	06/17/1980	Latos			
gag	4	3	1	7	6	9	8	03/02/1982	Christol, et al.			
	4	3	2	8	0	6	8	05/04/1982	Curtis			
	4	3	6	7	0	4	4	01/04/1983	Booth, Jr, et al			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
gag	0	5	1	1	4	4	8	11/4/1992	EP Application				
	0	7	5	3	9	1	2	01/15/1997	EP Application				
gag	2	2	9	3	7	9	5	04/10/1996	Great Britain				
	0	7	0	9	8	7	7	05/01/1996	EP Application				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

gag	PCT International Search Report dated September 2, 1999	
	European Search Report dated September 4, 2001, P.B. 5818- Patentlaan 2, 2280 HV Rijswijk (ZH), The Hague	
EXAMINER	George Gaudreau	DATE CONSIDERED 5-04/

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